

AMICSA 2022

Thursday, 2 June 2022

Radiation tests of analogue and mixed-signal ICs: Radiation tests of analogue and mixed-signal ICs (1/2) (13:00 - 13:25)

time	[id] title	presenter
13:00	[17] Flexible Test System for Single Event Effect (SEE) Characterization of Digital and Mixed-Signal Integrated Circuits	Dr CARRANZA GONZÁLEZ, Luis

Radiation tests of analogue and mixed-signal ICs: Radiation Test (15:00 - 15:55)

time	[id] title	presenter
15:00	[8] Validation, Characterization and Irradiation Testing of the DARE65T Platform	VAN DE BURGWAL, Marcel
15:30	[12] Detailed SET Ionized Charge and Pulse Duration Measurement of a 65 nm CMOS Technology	LI, Zheyi